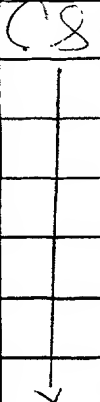


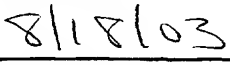
 <p><b>INFORMATION DISCLOSURE CITATION</b> (Use several sheets if necessary)</p>				Docket Number (Optional) <b>C-531/470</b>		Application Number <b>10/034,005</b>		
				Applicant(s) <b>Parris et al.</b>				
				Filing Date <b>12/28/01</b>		Group Art Unit <b>1755</b>		
<b>U.S. PATENT DOCUMENTS</b>								
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
	AA	4,289,678 A	09/15/81	Calder et al.	260	33.6 UA	10/16/79	
	AB	4,460,732 A	07/17/84	Buscall et al.	524	460	06/17/83	
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<b>FOREIGN PATENT DOCUMENTS</b>								
	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO
	BA	EP 0 796 876 A1	09/24/97	WIPO	C08F	212/08		
	BB	JP 2103274 A	04/16/90	Japan (Abstract)	C09D	11/00		
	BC	JP 7053612 A	02/28/95	Japan (Abstract)	C08F	002/44		
	BD	JP 7181715 A	07/21/95	Japan (Abstract)	G03G	009/08		
	BE	JP 8143804 A	06/04/96	Japan (Abstract)	C09D	011/00		
<b>OTHER DOCUMENTS</b> (Including Author, Title, Date, Pertinent Pages, Etc.)								
EXAMINER 					DATE CONSIDERED 			

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

